

<b>Notice of References Cited</b>	Application/Control No. 10/566,346		Applicant(s)/Patent Under Reexamination VAN BEEK ET AL.	
	Examiner MARJAN FARDANESH		Art Unit 3777	Page 1 of 1

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*	B	US-6,014,204	01-2000	Prahl et al.	356/73
*	C	US-6,124,597	09-2000	Shehada et al.	250/461.2
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	K	US-			
	L	US-			
	M	US-			

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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